NAPSON CORPORATION

CALTRON PTE LTD

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BUILT-IN NON-CONTACT TYPE RESISTANCE MEASUREMENT MODULE

NC-110 (NC-110PV)

- Multi-point, Non-Contact Type using Eddy Current method
- In-Line built-in module for production line and transportation system
- Possible to measure sheet resistance without contact with maximum of 3 types of probes
- Connect to host PC by LAN to send measurement command and data
- Measure Range depends on selected Probe type
- Sample Size:
  - ✓ Ø 6” to 8” (Ø 12” optional)
  - ✓ 156mm x 156mm (210mm x 210mm optional)

MEASURE RANGE

PARAMETER	LOW PROBE TYPE	MIDDLE PROBE TYPE	HIGH PROBE TYPE	S-HIGH PROBE TYPE
RESISTIVITY (Ω.cm)	0.001 to 0.05	0.05 to 0.5	0.5 to 60.0	60.0 to 200.0
SHEET RESISTANCE (Ω/Sq)	0.01 to 0.5	0.5 to 10.0	10.0 to 1k	1k to 3k

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC, etc)
- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire, etc)
- Conductive thin film (Metal, ITO etc)
- Chemical compound semiconductor (GaAs Epi, GaN Epi, InP, Ga, etc)
- Others: On Request

BUILT-IN NON-CONTACT TYPE RESISTANCE MEASUREMENT MODULE

NC-600 / NC-700

- Multi-point, Non-Contact Type using Eddy Current method
- In-Line built-in module for production line; such as PET film, Flat Panel Display, Glass, or Paper
- Continuous measurement in Roll to Roll with OFF-SET FREE capability
- Measure Range depends on selected Probe type
- Sample Size: On Request

MEASURE RANGE

PARAMETER	LOW PROBE TYPE	MIDDLE PROBE TYPE	HIGH PROBE TYPE	S-HIGH PROBE TYPE
RESISTIVITY (Ω.cm)	0.001 to 0.05	0.05 to 0.5	0.5 to 60.0	60.0 to 200.0
SHEET RESISTANCE (Ω/Sq)	0.01 to 0.5	0.5 to 10.0	10.0 to 1k	1k to 3k

APPLICABLE MATERIALS

- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire, etc)
- Conductive thin film (Metal, ITO etc)